

Tue, 02.07.	K6	Brüssel	K9	K3	K4	K7	K5
10:35 - 12:05	Special session: Self-optimizing production systems Cathrin Wesch-Potente RWTH Aachen University, Germany	Microprobe systems Dr. Henny Spaan IBS Precision Engineering, Netherlands	Sensors and actuators: actuators Prof. Kuang-Chao Fan National Taiwan University, Taiwan	Optical metrology: optical probing Prof. Yuri Chugui Technological Design Institute of Scientific Instrument Engineering, Russia	Intelligent instruments for automation: Smart systems Dr. Emilio Prieto Centro Español de Metrologia (CEM), Spain	Sensors and actuators: general Dr. Patrich Beajeau RWTH Aachen University, Germany	Management of measurement processes Dr. Edward Morse UNC Charlotte, United States of America
14:15 - 15:30	Special session: Self-optimizing production systems Prof. Illés Dudás University of Miskilc, Hungary	Nanometrology Prof. Kiyoshi Takamasu University of Tokyo, Japan	Calibration and machine tool performance: Calibration procedures Prof. Ping Cai Shanghai Jiao Tong University, China	In-process and Inline metrology Prof. Jürgen Czarske Technical University of Dresden, Germany	Position & displacement metrology: interferometry Prof. Ming Wang Nanjing Normal University, China	Metrology for SI Dr. Martin Milton Bureau International des Poids et Mesures, France	Management of measurement processes Prof. Chao-Ching Ho National Yunlin University of Science and Technology, Taiwan
15:50 - 17:20	Special session: Towards zero defect manufacturing Andreas Witte RWTH Aachen University, Germany	Micro & nano metrology: instrumentation Dr. Richard Leach National Physical Laboratory, Great Britain	position & displacement metrology: encoder systems Dr. Tsukasa Watanabe National Metrology Insitute of Japan, Japan	Optical metrology: image processing Dr. Sophie Gröger Technical University of Chemnitz, Germany	Position & displacement metrology: interferometry Dr. So Ito Tohoku University, Japan	Sensors and actuators: optical and electrical systems Prof. Weijie Dong Dalian University of Technology, China	Management of measurement processes Prof. Gustavo Donatelli CERTI, Brazil
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10:30 - 12:15	Material properties' characterization tbd.	Dimensional metrology for small features Dr. Michael Totzeck Carl Zeiss AG, Germany	Calibration and machine tool performance: Machine tool performance Dr. Fang-Jung Shiou National Taiwan University of Science and Technology, Taiwan	Optical metrology: optical systems tbd.	Surface Metrology Dr. Han Haitjema Mitutoyo Research Center Europe, Netherlands		Intelligent instruments for automation: Manufacturing integration Prof. Zhaoyao Shi Beijing University of Technology, China
13:30 - 14:45	Measurements, modeling and simulation in the humanitarian field Dr. Kseniia Syzozhnikova D.I.Mendeleyev Institute for Metrology, Russia Co-Chair Petrov, Roland Taymanov	Nanometrology tbd.	Calibration and machine tool performance: Calibration procedures Dr. Yohan Kondo National Metrology Insitute of Japan, Japan	In-process and Inline metrology Dr. Yongsheng Gao Hong Kong University of Science and Technology, China	Position & displacement metrology: interferometry Prof. Seung-Woo Kim KAIST, Korea	Macro Metrology Dr. Frank Härtig, Physikalisch-Technische Bundesanstalt PTB, Germany	Management of measurement processes Prof. Sarwat Zahwi National Institute for Standards (NIS), Egypt